

Notice of References Cited	Application/Control No. 10/620,461	Applicant(s)/Patent Under Reexamination MISAWA, TAKESHI	
	Examiner Thomas J. Magee	Art Unit 2811	Page 1 of 1

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	B	US-5,523,174	06-1996	Masanori Tamaki	428/669
	C	US-6,395,124 B1	05-2002	Joel D. Oxman et al.	156/275.5
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NON-PATENT DOCUMENTS

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.